

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hideomi Suzawa et al.	
		Filing Date May 11, 2001	Group Art Unit 2812

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Sub-class	Filing Date If Appropriate
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							Yes No
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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Examiner Signature	Date Considered
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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